The Influence of Substrate in Determining the Band Gap of Metallic Carbon Nanotubes

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ABSTRACT: We report a detailed comparison of ultraclean suspended and on-substrate carbon nanotubes (CNTs) in order to quantify the effect of the substrate interaction on the effective band gap of metallic nanotubes. Here, individual CNTs are grown across two sets of electrodes, resulting in one segment of the nanotube that is suspended across a trench and the other segment supported on the substrate. The suspended segment shows a significant change in the conductance ($\Delta G/G = 0.84$) with applied gate voltage, which is attributed to a small band gap. The on-substrate segment, however, only shows a change in the measured conductance of $\Delta G/G = 0.11$. A Landauer model is used to fit the low bias conductance of these devices. From these fits, the band gaps in the suspended region range from 75 to 100 meV but are only 5–14.3 meV when the nanotube is in contact with the substrate. The decreased band gap is attributed to localized doping caused by trapped charges in the substrate that result in inhomogeneous broadening of the Fermi energy, which in turn limits the ability to modulate the conductance.

KEYWORDS: Conductance, band gap, quasi-metallic, energy dispersion relation

Metallic carbon nanotubes are known to exhibit small band gaps on the order of 10–100 meV.¹ The origin and magnitude of these band gaps, however, is still a topic of debate. Early scanning tunneling microscopy (STM) studies of metallic nanotubes attributed these small energy gaps to the curvature of the nanotube.² Tight binding calculations for armchair and metallic zigzag nanotubes do not predict the existence of a band gap in the electronic structure.³ More recent calculations of metallic nanotubes show a small band gap caused by breaking of the bond symmetry due to curvature.²,⁴⁻⁶ Uniaxial strain can also result in a band gap in metallic nanotube.⁷,⁸ These types of symmetry-breaking band gaps (i.e., strain-induced, curvature-induced), however, can be closed with the application of an axial magnetic field. This, however, was not observed experimentally,¹ indicating that another underlying mechanism is responsible for the observed band gaps. The relatively large band gaps observed in ultraclean, suspended small gap metallic (i.e., quasi-metallic) carbon nanotubes have been attributed to a Mott insulator transition arising from strong electron–electron interactions.¹ However, this mechanism has not been confirmed by other experiments, and the exact nature of the Mott state is not known, whether it exhibits a charge density wave, spin density wave, or otherwise.⁹,¹⁰ A large suppression of the Raman intensity has been correlated to the magnitude of the band gap in quasi-metallic nanotubes, which could result from a lattice distortion induced by a charge density wave.¹¹ Another possible mechanism for the observed energy gap is a Peierls distortion,¹² which results from strong electron–phonon interactions. First principles calculations have predicted a Peierls transition at temperatures as high as 300 K¹³ for small diameter metallic CNTs with band gaps in the order of 0.25 eV.¹⁴ While a Peierls distortion would result in a band gap and a large modulation of the Raman intensity through a lowering of the crystal symmetry, it has been predicted theoretically only in nanotubes with very small diameters and is not expected to occur in the relatively large diameter nanotubes grown in most experimental studies. Several phenomena have been observed in these ultraclean, suspended, nearly defect-free, metallic carbon nanotubes near zero gate voltage, including breakdown of the Born–Oppenheimer approximation (BOA),¹⁵ thermal nonequilibrium phonon populations,¹⁶ and large Raman intensity modulations.¹¹ Yet, to date, no detailed comparison of these band gaps on- and off-substrate has been made.

In this work, we perform a detailed comparison of CNTs grown on- and off-substrate in order to quantify the effect of the substrate interaction on the band gap of quasi-metallic nanotubes. We grow CNTs across two sets of electrodes, resulting in one segment of the nanotube suspended across a trench and the other segment supported on the substrate, as shown in Figure 1a,b. By comparing the band gaps of the same exact nanotube on- and off-substrate, we eliminate the variations associated with different nanotube chiralities and growth conditions. We then characterize the band gaps of these samples by fitting the $I$–$V_{gate}$ characteristics to a Landauer

**Figure 1:**

- **Left Panel:** Diagram of the nanotube sample with a back gate and forward bias.
- **Right Panel:** Graph showing the conductance vs. gate voltage for suspended and on-substrate nanotubes.
transport model in order to identify the effect of the substrate on the electronic properties of quasi-metallic nanotubes. Devices in this study are fabricated by first etching a 500 nm deep trench in a Si/SiO₂/SiN substrate. Pt electrodes are patterned on top of the substrate using photolithography. Iron nanoparticle catalyst is then deposited on top of one of the electrodes close to the trench, as shown schematically in Figure 1a. Carbon nanotube growth is carried out at 875 °C for 15 min by flowing a mixture of argon, ethanol, and hydrogen. Figure 1b shows a scanning electron microscope (SEM) image of a final device. The \( I-V_{\text{bias}} \) characteristics of the suspended CNT device are used to ensure that the device consists of only one nanotube, if the maximum current (in μA) satisfies the approximate relation \( I_{\text{max}} \sim 10/L \), where \( L \) is the length of the nanotube, as established by Pop et al.\textsuperscript{17}

Figure 2a shows the measured \( I-V_{\text{bias}} \) characteristics of the suspended and on-substrate regions taken from the same nanotube. The blue solid curve is for the suspended portion and the red dashed curve is for the on substrate portion. \( I-V_{\text{gate}} \) characteristics of the suspended and on-substrate regions are plotted as a function of gate voltage. We used the Pt gate electrode to measure the conductance of the suspended segment while the Si back gate was used to measure the on substrate segment. For the suspended segment of the nanotube, the measured conductance drops from 33.1 μS at \( V_g = -10 \) V to 5.3 μS at the charge neutrality point, giving a conductance modulation of \( \Delta G/G_{\text{max}} = 0.84 \). Whereas, for the on-substrate segment, the conductance changes by only \( \Delta G/G_{\text{max}} = 0.11 \). In order to illustrate the drastic difference in conductance of each nanotube segment, Figure 2c shows the normalized conductance (\( G/G_{\text{max}} \)) plotted as a function of gate voltage.

**Figure 1.** (a) Cross-sectional diagram and (b) SEM image of a carbon nanotube sample for comparing on-substrate and suspended CNT devices.

**Figure 2.** (a) \( I-V_{\text{bias}} \) characteristics of the suspended and on-substrate regions taken from the same nanotube. The blue solid curve is for the suspended portion and the red dashed curve is for the on substrate portion. (b) \( I-V_{\text{gate}} \) characteristics of the suspended and on-substrate regions. (c) Normalized conductance (\( G/G_{\text{max}} \)) plotted as a function of gate voltage.
of the band gap in the metallic nanotube when it is in contact with the substrate. We believe the primary effect of the substrate in determining the effective band gap is trapped charges. Other effects, such as diameter deformation, can also lead to change in the band gap.19 However, these changes would result in a decrease in band gap for some chiralities and an increase for others, which is not observed experimentally. In order to quantify the changes observed in the effective band gap, we fit the $I-V_{\text{gate}}$ data using a Landauer model, as discussed previously.16 Briefly, the low bias conductance of the device can be expressed as

$$G = \left(\frac{4e^2}{h}\right) \int_{-\infty}^{\infty} \frac{\lambda_{\text{eff}}}{\lambda_{\text{eff}} + L} \left(\frac{-\partial f}{\partial E}\right) dE$$

where $\lambda_{\text{eff}}$ is the effective mean free path (given by Matthiessen rule), $L$ is the device length, and $\partial f/\partial E$ is the derivative of the Fermi–Dirac distribution.20 Using a hyperbolic energy dispersion relation, we integrate over the density of states which is given by

$$D(E) = \sum_{j=1}^{N} \left| \frac{dE_f(k)}{dk} \right|^{-1}$$

Here, the density of states is zero inside the band gap, $E_g$. Figure 3a shows a fit of the suspended $I-V_{\text{gate}}$ characteristics using this model with $E_g = 100$ meV. Using the same nanotube parameters in the fit (i.e., diameter), the on-substrate data is fitted by decreasing the band gap of the device to $E_g = 5$ meV, as shown in Figure 3b.

The Fermi energy in the nanotube is related to the applied gate voltage according to the following relation:

$$E_F + \frac{Q}{C} = eV_{\text{gate}}$$

where $E_F$ is the Fermi energy, $Q$ is the electric charge on the nanotube, and $C$ is the geometric capacitance. In our initial fits, the capacitance per unit length was calculated using the formula $C' = 2\pi\varepsilon\varepsilon_0/\ln(4h/d_t)$, where $h$ and $d_t$ are the dielectric thickness (1 μm) and the nanotube diameter (1.3 nm), respectively.23 From the schematic diagram of Figure 1a, the gates for the on-substrate and suspended segments are structurally different. This geometric difference can significantly affect the capacitive coupling and gating effect. These different geometries result in capacitance values of 8.05 and 20.6 pF/μm for the suspended and on-substrate segments, respectively. We found that these fits could be improved by decreasing these capacitance values to 7 and 10 pF/μm. While these changes in the capacitance improve the fits, they do not change the value of the band gap, which is strongly affected by the relative value of minimum conductance $\Delta G/G$. Figure 3c shows the Fermi energy plotted as a function of the gate voltage, using the band gap and capacitance values in eqs 2 and 3. The Fermi energy of the suspended segment exhibits significant nonlinear behavior due to its relatively large band gap ($E_g = 100$ meV), while the on-substrate Fermi energy shows almost linear behavior, as expected for a metallic nanotube with little or no band gap. In Table 1, we list the change in conductance and band gaps of four samples measured using this approach.

We believe this reduction in the effective band gap is due to localized doping of the nanotube by trapped charges in the substrate, which results in a spatially varying Fermi energy, as illustrated schematically in Figure 3d. This results in an inhomogeneous broadening of the Fermi energy, as illustrated schematically in Figure 3d. The spatial variation of the Fermi energy in graphene on SiO$_2$ and hexagonal boron nitride has

$$E_F + \frac{Q}{C} = eV_{\text{gate}}$$

$$D(E) = \sum_{j=1}^{N} \left| \frac{dE_f(k)}{dk} \right|^{-1}$$

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recently been mapped using scanning tunneling microscopy (STM).24 On SiO₂, the local Fermi energy was found to vary by as much as 100 meV, which is consistent with our measurements on carbon nanotube devices. It is these fluctuations in the Fermi energy that have made it difficult to observe the band gap in bilayer graphene, unless it is deposited on h-BN.25 The effective band gaps extracted from the Landauer model are the result of the substrate obscuring the band gap rather than an inherent modulation of the intrinsic band gap of the nanotube. The appropriate interpretation is that all metallic carbon nanotubes have large band gaps that are typically obscured by the fluctuations in the local Fermi energy when supported by a Si/SiO₂ substrate.

The large effective band gaps observed in the conductance of the suspended segment is the breaking of the crystal symmetry due to curvature. Theoretically, the curvature induces a band gap of a 1.3 nm diameter nanotube has been predicted to lie between 26 and 35 meV,2,26 which is 3–4 times smaller than the band gaps reported in Table 1 for the suspended segment. This particular region may exhibit curvature induced band gap as a secondary effect but there may be other phenomenon contributing to the large band gaps, as described in the introduction of this paper.

In conclusion, we have characterized carbon nanotube devices with one segment of the nanotube suspended and the other segment lying on the substrate. The suspended segment shows a significant change in the conductance ($\Delta G/G = 0.84$) as a function of gate voltage, while the on-substrate segment shows a small change of $\Delta G/G = 0.11$. A Landauer model is used to fit the effective band gap of each segment, resulting in values that range between 75 and 100 meV for the suspended segment and 5–14.3 meV for the on-substrate segment. This change in the effective band gap is attributed to an alteration in the electronic properties of the nanotube due to trapped charges in the substrate, which creates fluctuations in the Fermi energy.

### REFERENCES

